

February 2008

FDMS8670S N-Channel PowerTrench[®] SyncFETTM 30V, 42A, 3.5m Ω

Features

- Max $r_{DS(on)} = 3.5 \text{m}\Omega$ at $V_{GS} = 10 \text{V}$, $I_D = 20 \text{A}$
- Max $r_{DS(on)} = 5.0 \text{m}\Omega$ at $V_{GS} = 4.5 \text{V}$, $I_D = 17 \text{A}$
- Advanced Package and Silicon combination for low r_{DS(on)} and high efficiency
- SyncFET Schottky Body Diode
- MSL1 robust package design
- RoHS Compliant

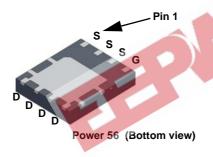


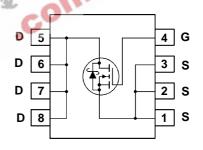
General Description

The FDMS8670S has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{\text{DS}(\text{on})}$ while maintaining excellent switching performance. This device has the added benefit of an efficient monolithic Schottky body diode.

Application

- Synchronous Rectifier for DC/DC Converters
- Notebook Vcore/ GPU low side switch
- Networking Point of Load low side switch
- Telecom secondary side rectification





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			30	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		42	
	-Continuous (Silicon limited)	T _C = 25°C		116	
I _D	-Continuous (Silicon limited)	T _C = 100°C		74	Α
	-Continuous	T _A = 25°C		20	
	-Pulsed			200	
	Power Dissipation	T _C = 25°C		78	
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.5	W
	Power Dissipation	T _A = 85°C	(Note 1a)	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{ heta JC}$	Thermal Resistance, Junction to Case		1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8670S	FDMS8670S	Power 56	13"	12mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted **Parameter**

Off Characteristics							
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 1mA$, $V_{GS} = 0V$	30			V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 10mA, referenced to 25°C		17		mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V$, $V_{GS} = 0V$			500	μΑ	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA	

Test Conditions

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On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1mA$	1	1.5	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 50mA, referenced to 25°C		-2.8		mV/°C
		$V_{GS} = 10V, I_D = 20A$		2.8	3.5	
r _{DS(on)}	()	$V_{GS} = 4.5V, I_D = 17A$		3.6	5.0	mΩ
		$V_{GS} = 10V$, $I_D = 20A$, $T_J = 125$ °C		3.9	6.0	
9 _{FS}	Forward Transconductance	$V_{DS} = 10V, I_D = 20A$		98		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 0V	3005	4000	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V$ f = 1MHz	865	1150	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	320	480	pF
R _a	Gate Resistance	f = 1MHz	1.4	5.0	Ω

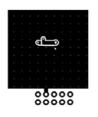
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		14	26	ns
t _r	Rise Time	$V_{DD} = 15V, I_D = 20A$ $V_{GS} = 10V, R_{GEN} = 5\Omega$	19	35	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 322$	37	60	ns
t _f	Fall Time		10	20	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0V to 10V	52	73	nC
Q _{g(4.5V)}	Total Gate Charge at 4.5V	$V_{GS} = 0V \text{ to } 4.5V$ $V_{DS} = 15V$	24	34	nC
Q_{gs}	Gate to Source Gate Charge	I _D = 20A	8		nC
Q_{gd}	Gate to Drain "Miller" Charge		10		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 2A$		0.4	0.7	V
t _{rr}	Reverse Recovery Time	I _E = 20A, di/dt = 300A/μs		26	42	ns
Q_{rr}	Reverse Recovery Charge	$-1_{\rm F} = 20$ A, di/dt = 300 A/ μ S		24	39	nC

R_{θJA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{θJC} is guaranteed by design while R_{θCA} is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper

b. 125°C/W when mounted on a minimum pad of 2 oz copper

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2: Pulse time < $300\mu s$, Duty cycle < 2%.

Typical Characteristics T_J = 25°C unless otherwise noted

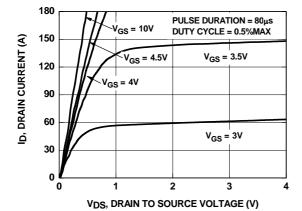


Figure 1. On Region Characteristics

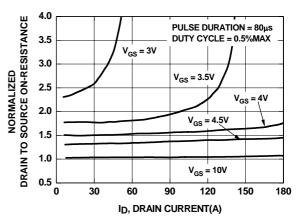


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

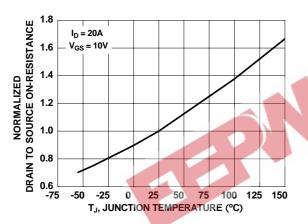


Figure 3. Normalized On Resistance vs Junction Temperature

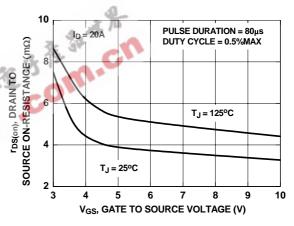


Figure 4. On-Resistance vs Gate to Source Voltage

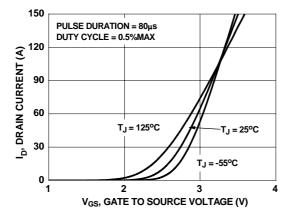


Figure 5. Transfer Characteristics

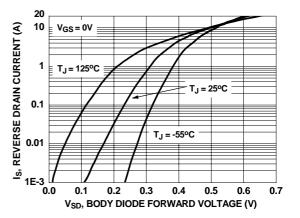


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

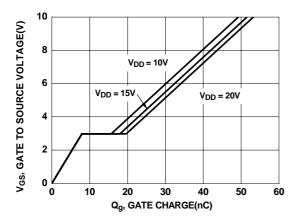


Figure 7. Gate Charge Characteristics

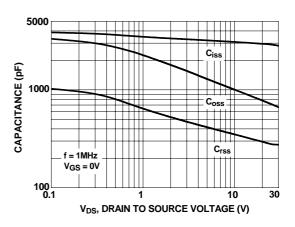


Figure 8. Capacitance vs Drain to Source Voltage

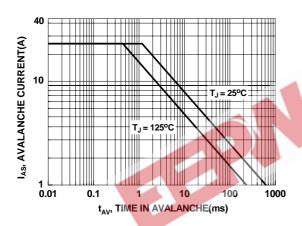


Figure 9. Unclamped Inductive Switching Capability

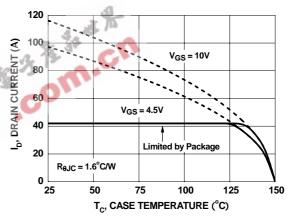


Figure 10. Maximum Continuous Drain Current vs Case Temperature

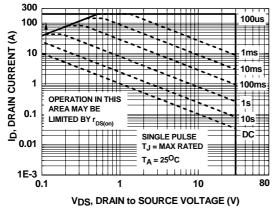


Figure 11. Forward Bias Safe Operating Area

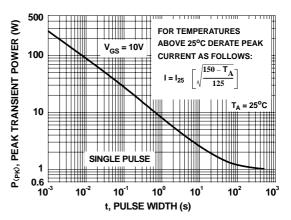


Figure 12. Single Pulse Maximum Power Dissipation



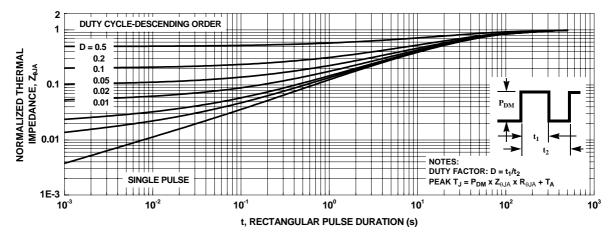


Figure 13. Transient Thermal Response Curve



Typical Characteristics (continued)

SyncFET Schottky body diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverses recovery characteristic of the FDMS8670S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

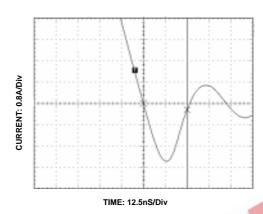


Figure 14. FDMS8670S SyncFET Body Diode reverse recovery characteristics

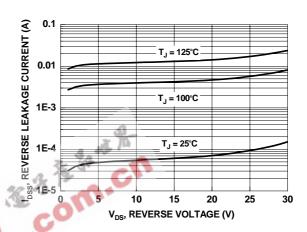
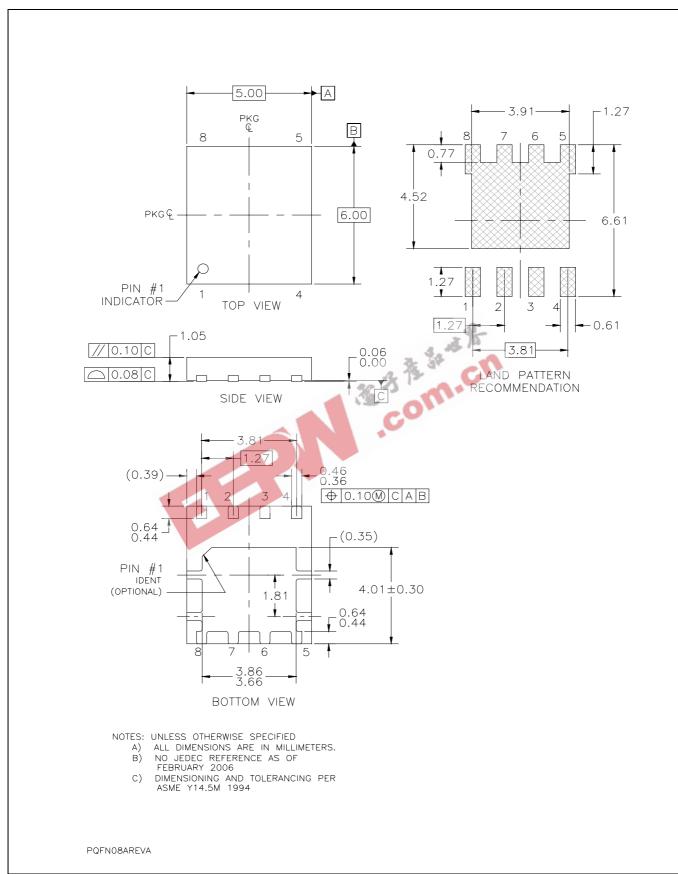


Figure 15. SyncFET Body Diode reverse leakage vs drain to source voltage







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